



# <span id="page-0-0"></span>**Features and Benefits 1.**

- **Sensor interface IC for use in harsh** automotive environments
- High EMC robustness
- **Possibilities to achieve outstanding overall** sensor performances
- **SENT** output with option for pressure, calibrated on chip or external NTC temperature information
- **Outstanding accuracy for factory** calibrated NTC within ±1°C

# <span id="page-0-1"></span>**Application Examples 2.**

- **Piezoresistive automotive pressure sensors** interface
- Sensors based on Wheatstone bridge resistors

# <span id="page-0-2"></span>**Ordering information 3.**



### Legend:



# <span id="page-0-3"></span>**Functional Diagram 4.**









# <span id="page-1-0"></span>**General Description 5.**

The MLX90329 covers the most typical resistive type of Wheatstone bridge applications for use in an automotive environment. It is a mixed signal sensor interface IC that converts small changes in resistors, configured in a full Wheatstone bridge on a sensing element, to large output voltage variations.

The signal conditioning includes gain adjustment, offset control as well as temperature compensation in order to accommodate variations of the different resistive sensing elements. Compensation values are stored in EEPROM and can be reprogrammed with a Melexis tool including the necessary software. The MLX90329 is programmed with a single wire serial interface through the output pin.

The user can specify SENT fast channel configuration, slow channel messages and enable several diagnostic settings. By intercepting these various fault modes, the MLX90329 is able to inform about the reliability of its output signal.



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### **Contents**



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## <span id="page-3-0"></span>**Glossary of Terms 6.**

POR: Power-on Reset ADC: Analog to Digital Converter DSP: Digital Signal Processor EMC: Electro Magnetic Compatibility SENT: Single Edge Nibble Transmission OV: Over Voltage UV: Under Voltage FC: SENT Fast Channel FC1: SENT Fast Channel 1 FC2: SENT Fast Channel 2

## <span id="page-3-1"></span>**Absolute Maximum Ratings 7.**



#### *Table 1: Absolute maximum ratings*

Exceeding the absolute maximum ratings may cause permanent damage. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## <span id="page-3-2"></span>**Pin Definitions and Descriptions 8.**



*Table 2: Pin out definitions and descriptions* 







*Table 3: Package marking definition* 

## <span id="page-4-0"></span>**General Electrical Specifications 9.**

DC Operating Parameters  $T_A = -40^{\circ}C$  to 150°C



<sup>1</sup> Typical values are defined at  $T_A$  = +25°C and  $V_{DD}$  = 5V.

*2 Number of SENT frames between pressure step and settled output (last frame containing stable pressure data)* 

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### <span id="page-5-0"></span>**Filters 10.**

There are two filters available to filter the pressure signal. The first filter is a Small Signal Filter which can be disabled or enabled. The second filter is a first order low pass filter for the pressure signal which has a programmable depth.

An overview of the noise levels using different filter and gain combinations can be found in [Table 6.](#page-7-0)

### <span id="page-5-1"></span>10.1. PFLT

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PFLT is a programmable first order low pass filter. The depth of this filter can be selected. This filter can be configured to select the optimal trade-off between response time and output noise.

<sup>&</sup>lt;sup>3</sup> A maximum performance can be obtained with this sensor sensitivity range. A programmable gain with 5 bits from a gain of 9 to 237 is used in the *analog front end circuitry to adapt the sensor range to the on chip ADC input range. Half of the ADC input range (= 1.75V) is foreseen to be used during the sensor calibration at the first temperature. The rest of the ADC input range is left for the compensation of the s ensor temperature effects. A coarse offset compensation is available to calibrate large sensor offsets.* 

A more detailed overview of the gains in the analog frontend can be found in [Table 7.](#page-9-0)<br><sup>4</sup> Please contact Melexis for assistance in evaluating the match between the sensing element and the MLX90329 interface if needed.





The low pass filter is implemented according to the following formula:

$$
Filter_{output}(k) = \frac{Filter_{input}(k) - Filter_{output}(k-1)}{2^{PFLT}} + Filter_{output}(k-1)
$$

The PFLT parameter in the formula is set in EEPROM and can have a value between 0 and 9. An overview of typical response times when applying a step on the input using different PFLT filter settings can be found in [Table](#page-6-1)  [5.](#page-6-1) The number of SENT frames indicated in the table includes the last frame which contains stable pressure data. Filter setting 0 disables the PFLT.

<b>PFLT</b> setting	<b>Response time</b> in SENT frames <sup>(5)</sup>
0	3
$\mathbf{1}$	3
$\overline{2}$	5
3	8
4	13
5	24
6	45
7	88
8	176
9	350

*Table 5: Filter settings with corresponding typical response times* 

### <span id="page-6-1"></span><span id="page-6-0"></span>10.2. SSF

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The SSF (Small Signal Filter) is a digital filter which is designed not to have an impact on the response time of a fast changing pressure signal like a pressure step. When a large signal change at the input is present, the filter is bypassed and not filtering the signal. For small signal changes, which are in most cases noise, the filter is used and filtering the pressure signal.

The Small Signal Filter can be enabled or disabled in EEPROM. It is advised not to use the SSF in combination with the PFLT enabled.

*<sup>5</sup> Tick time is set to 3us and Pause Pulse is enabled.*







<span id="page-7-0"></span>*Table 6: Filter settings and gain combinations with corresponding pressure noise values* 



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## <span id="page-8-0"></span>**Analog Front End 11.**

The analog front end of the MLX90329 consists of a chopping stage and 3 amplification stages as can be seen in [Figure 2.](#page-8-1) There are also several input diagnostics integrated into this front end to be able to detect a broken InP or InN connection or an input which is out of range. This diagnostic information is transferred to the microcontroller to handle further action for example flagging a diagnostic message.



*Figure 2: Analog front end block diagram* 

<span id="page-8-1"></span>The first stage is an instrumentation amplifier of which the gain can be programmed using 3 bits to cover a gain range between 4.5 and 10.6.

Transfer equation:

OUTP1 – OUTN1 = Gst1\*(InP – InN) in phase 1  $OUTP1 - OUTN1 = Gst1*(InN - InP)$  in phase 2

The second stage is a fully differential amplifier. The gain of the amplifier can be calibrated using 1 bit. Transfer equation:

OUTP2 – OUTN2 = -Gst2\*(OUTP1 – OUTN1) – Gst2\*(CSOF1 – CSOF2) in phase 1 OUTP2 – OUTN2 = -Gst2\*(OUTN1 – OUTP1) – Gst2\*(CSOF2 – CSOF1) in phase 2

The CSOF1 and CSOF2 signals are generated by the coarse offset DAC with the following transfer functions:

$$
CSOF1 = \frac{VDDA}{2} + (-1)^{CO7} * \left(\frac{2}{3} - \frac{1}{3}\right) * \frac{VDDA}{2} * \frac{CO[6:0]}{127}
$$
  
\n
$$
CSOF2 = \frac{VDDA}{2} - (-1)^{CO7} * \left(\frac{2}{3} - \frac{1}{3}\right) * \frac{VDDA}{2} * \frac{CO[6:0]}{127}
$$

CO[6:0] fixes the DAC output. CO7 is used for the polarity.

The third stage is an integrator which is controlled using 2 bits to set a gain between 1.6 and 6.4 Transfer equation at the outputs of the amplifier: OUTP3 – OUTN3 = -N\*(C1/C2)\*(OUTP2 – OUTN2) OUTP3\_common\_mode and OUTN3\_common\_mode = VCM = VDDA/2

In this equation N represents the number of integration cycles which is a fixed value of  $N = 40$ .

C2 is a fixed feedback capacitor of approximately 5pF. C1 can have 3 different values: 0.2pF, 0.4pF or 0.8pF.

Transfer equation after the ADC: Pressure  $ADC = ((OUTN3 – OUTP3)*2<sup>16</sup>/VDDA) + 32768$ 





An overview of all possible values for Gst1, Gst2 and Gst3 can be found in [Table 7](#page-9-0) below. The input stage is designed to work with an input common-mode voltage range between 42%Vbrg and 58%Vbrg.



<span id="page-9-0"></span>*Table 7: Gain and input signal range of the analog front end* 





## <span id="page-10-0"></span>**ADC 12.**

The 16 bit differential ADC has a range from –VDDA/2 to +VDDA/2.

There are 7 different ADC channels. Channel 0 is not used. [Table 8](#page-10-2) below describes all the channels.



### *Table 8: ADC channels*

<span id="page-10-2"></span>The different channels are converted in a constantly repeating sequence at a rate of 50µsec for each individual conversion. The order is shown in [Figure 3](#page-10-3) below.

<span id="page-10-3"></span>

*Figure 3: ADC sequence* 

## <span id="page-10-1"></span>**Digital 13.**

The digital is built around a 16-bit microcontroller. It contains besides the processor also ROM, RAM and EEPROM and a set of user and system IO registers.

Temperature compensation of the pressure signal and pressure linearization is handled by the microcontroller. For the pressure compensation there are EEPROM parameters allocated to be able to cover a large variety of calibration approaches.

Both for gain and offset of the pressure signal, there is a separate temperature dependency programmable ranging from a temperature independence to a first order, second order and finally a third order compensation. This is reflected in EEPROM parameters for the offset (O0, O1, O2 and O3) and for the gain (G0, G1, G2 and G3). If required, the linearity of the pressure signal can also be compensated without a temperature dependency or with a first order temperature dependency through EEPROM parameters L0 and L1.

For the temperature compensation of the pressure signal both the internal on-chip PTAT temperature as the temperature measured using the sensor bridge resistance can be used. The selection between both can be set in EEPROM using the 'Tpress Select' parameter. Tpress Select = 0 corresponds to sensing element temperature reference and Tpress Select = 1 is on-chip PTAT temperature. When using the sensing element bridge resistance





temperature measurement, a selection of a 2K, 4K, 8K or a 32K bridge resistance can be done using EEPROM parameter 'BRIDGE SEL'<sup>(6)</sup>, see [Table 9.](#page-11-1)



#### *Table 9: Bridge resistance selection for temperature reference*

<span id="page-11-1"></span>Linearization of the NTC temperature is also covered partially by the microcontroller. More information in this topic can be found in chapter [14.](#page-11-0)

### <span id="page-11-0"></span>**14. NTC Temperature Linearization**

The linearization of the NTC temperature signal is split up in several stages. A schematic overview of these steps can be seen in [Figure 4.](#page-11-2)



#### *Figure 4: Block diagram NTC linearization*

<span id="page-11-2"></span>The complete system can be divided into 5 separate stages.

- 1. A resistor divider with internal resistor Rs is used to linearize Rntc into a voltage.
- 2. A fully differential amplifier with unity gain is used to drive the ADC.
- 3. The 16-bit ADC is being used to convert the analog resistor divider output voltage into a digital signal called ADC\_raw.
- 4. With the help of calibration data saved in EEPROM the microcontroller will perform a first compensation on ADC\_raw converting in to ADC\_comp. This new value is targeted to be as close as possible to the value ADC\_ROM.
- 5. Finally a look up table (LUT) will be used to convert the ADC\_ROM values into the Tntc value which is the desired linearized NTC temperature.

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*<sup>6</sup> It is not mandatory to have a bridge resistance identical to the resistance selection setting. In this case it is advised to select the setting closest to the actual value. In case support is needed please contact Melexis.*





The default NTC characteristic which is calibrated can be found in [Table 10.](#page-12-0) When using an NTC which does not match the coefficients described above, it is advised to contact Melexis.

The EEPROM coefficients which are used for the conversion from ADC raw to ADC comp are N0 to N3, NO Diff\_Low to N3\_Diff\_Low, N0\_Diff\_High to N3\_Diff\_High and TEMP1 to TEMP3.



*Table 10: Default NTC characteristic* 

<span id="page-12-0"></span>The overall accuracy of the default NTC can be found in [Table 11.](#page-13-0) The default temperature characteristic of the NTC and the internal temperature signal can be found in the graph of [Figure 6.](#page-13-1)





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<span id="page-13-0"></span>

*Figure 5: NTC temperature accuracy* 

<span id="page-13-2"></span>

<span id="page-13-1"></span>*Figure 6: NTC and internal temperature transfer function* 



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## <span id="page-14-0"></span>**15. SENT Configuration**

The SENT output is designed to be compliant with the SAE J2716 rev. Apr 2016 SENT standard. The tick time is configurable in EEPROM using parameter TICK\_DIV. The available tick time settings are 3us, 4us, 6us, 10us, 12us and 16us. A pause pulse can also be enabled to have a fixed frame length of 282 ticks. This can be done using parameter PAUSE.

## <span id="page-14-1"></span>15.1. Fast Channel Configuration

On the fast channel, 8 different options are available to configure channel 1 and channel 2. An overview of these different options and how to configure them can be found i[n Table 12.](#page-14-2)



### *Table 12: Fast channel configuration options*

<span id="page-14-2"></span>The selection of the fast channel output mode can be done by changing the parameter 'FC\_CFG' in the EEPROM.

In case Medium temperature is selected to be available on fast channel 2, the type of media should be defined in EEPROM using parameter 'Tmedium\_Select'. When selecting 0, linearized NTC temperature will be available. Selecting 1 enables sensing element temperature. Sensing element temperature needs to be calibrated after connecting the sensing element to the MLX90329 and is not calibrated by Melexis<sup>(7)</sup>.

For Internal temperature, also two options are available defined in EEPROM parameter 'Tinternal Select' where 0 corresponds to on chip factory calibrated PTAT temperature and 1 corresponds to sensing element temperature. The same comment regarding the calibration of the sensing element temperature calibration as made above applies here.

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*<sup>7</sup> Contact Melexis for assistance if required.*





### <span id="page-15-0"></span>15.2. Slow Channel Configuration

The Slow Serial Channel is implemented according to the Enhanced Serial Message Format using 12 bit data and 8 bit message ID as described in the reference SENT protocol standard SAE J2716 rev. Apr 2016.

An overview of the different slow channel messages which are available in the MLX90329 can be found in [Table](#page-17-0)  [13.](#page-17-0) From this table 16 messages can be configured completely in EEPROM. The 12 bit data content of these messages can be configured freely. The ID of programmable message PR0, PR1, PR2 and PR3 is copied from EEPROM (2x 4 bit). The ID of PR5 is 1 bit higher than of PR4. The same is valid for the other pairs: PR6-7, PR8-9, …, PR14-15. This programmable ID is indicated i[n Table 13](#page-17-0) as 0xYZ.

All programmable messages can also be enabled and disabled, but not all independently of each other:

- PR0, PR1, PR2 and PR3 can be each independently enabled or disabled
- PR4 and PR5 are together enabled or disabled
- PR6 and PR7 are together enabled or disabled
- PR8, PR9, PR10 and PR11 are together enabled or disabled
- PR12, PR13, PR14 and PR15 are together enabled or disabled



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<span id="page-17-0"></span>*Table 13: Slow channel messages* 





Messages which have a "Y" in the column Rep of [Table 13](#page-17-0) can be selected to have a higher occurrence in the slow channel message sequence. Their repetition rate can be configured as indicated in [Table 14.](#page-18-0)

The repeatable messages MID01h, MID10h and MID23h can be configured individually to have their own repetition rate. The repetition factor setting can be done in respectively "SENT REP FACT ID 01", "SENT\_REP\_FACT\_ID\_10" and "SENT\_REP\_FACT\_ID\_23".

<b>Repetition Factor Setting</b>	<b>Real Repetition Factor</b>
0	Message repetition disabled
1	Message repeat every 2 messages
2	Message repeat every 3 messages
3	Message repeat every 4 messages
4	Message repeat every 5 messages
5	Message repeat every 6 messages
6	Message repeat every 7 messages
7	Message repeat every 8 messages
8	Message repeat every 9 messages
9	Message repeat every 10 messages
10	Message repeat every 12 messages
11	Message repeat every 16 messages
12	Message repeat every 20 messages
13	Message repeat every 24 messages
14	Message repeat every 28 messages
15	Message repeat every 30 messages

*Table 14: Repetition rate settings* 

<span id="page-18-0"></span>Once a message is configured to be repeatable, it will automatically have the highest priority. Therefore it will appear first in the slow message sequences.

The priority order between MID01, MID10 and MID23 can also be configured using EEPROM parameter "SC\_R\_O":

- SC\_R\_O = 0: Priority order: ID01h > ID10h > ID23h
- $\bullet$  SC\_R\_O = 1: Priority order: ID10h > ID23h > ID01h



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# <span id="page-19-0"></span>**16. Wrong Connections Overview**

[Table 15](#page-19-2) provides an overview of the behavior of the MLX90329 when different combinations of connections to GND, VDD and OUT are made.



<span id="page-19-2"></span><span id="page-19-1"></span>*Table 15: Wrong connections overview* 



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## <span id="page-20-0"></span>**17. Diagnostics**

### <span id="page-20-1"></span>17.1. Input Diagnostics

An overview of the different input diagnostics conditions and their corresponding fast channel mapping and diagnostic bit information in slow channel can be found in [Table 16.](#page-20-4)



*Table 16: Input diagnostics* 

### <span id="page-20-4"></span><span id="page-20-2"></span>17.2. Diagnostic Sources

The MLX90329 product has several internal checks which monitor the status of device. These checks or diagnostic sources can be enabled or disabled based on the sensor module requirements. An overview of the different diagnostic sources, their enable/disable parameter and the explanation of their functionality can be found below in table [Table 17.](#page-20-5)



*Table 17: Diagnostic sources* 

*8 See tables 17 to 19 for more information on the errors*

<span id="page-20-5"></span><span id="page-20-3"></span> $\overline{a}$ 





### 17.3. Fast and Slow Channel Diagnostics

There are two values reserved to show an error diagnostic mode in the fast channel. These values are 4090 and 4091. According to the type of diagnostic flag, one of the values will be transmitted if enabled. Internal errors like for example PRESS\_BROKEN\_W or PRESS\_PAR use 4090 to indicate an error condition on the fast channel.

Errors conditions which can be linked to external influences can be configured to either transmit 4090 or 4091. These errors are VSUP\_HIGH, VSUP\_LOW and T\_CHIP.

For both VSUP\_HIGH and VSUP\_LOW fast channel overwriting using an error message can even be disabled. This allows you to still decode properly the pressure or optionally temperature information in case of an over voltage or under voltage condition. The OV or UV condition can still be monitored using the status bits for FC1 and FC2 and the slow channel diagnostic message MID01.

An overview of the fast channel error configuration can be found in [Table 18.](#page-21-0) The EEPROM parameters V\_ERR, FCE\_VSUP and FCE\_TCHIP handle this configuration.



#### *Table 18: Fast channel error configuration*

<span id="page-21-0"></span>The diagnostic slow channel message (MID 1) can be enabled or disabled independent of the other slow channel messages and it has an adjustable repetition factor (2, 4, .., 30).

More information on the different diagnostics shown in SENT, their fast channel, slow channel and status bit mapping can be found in the tables below.







*Table 19: Diagnostics in fast channel configuration 0 - 3*







*Table 20: Diagnostics in fast channel configuration 4 - 7*







*Table 21: Diagnostics in slow channel*



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Multiple diagnostic errors can be flagged in the range 8xxh – FFFh in case parameter DIAG\_INT is set to 0.

The level of the over and under voltage diagnostics can be configured according to the ranges described in [Table](#page-25-1)  [22.](#page-25-1)



*Table 22: MLX90818 under and overvoltage detection* 

## <span id="page-25-1"></span><span id="page-25-0"></span>**Timings 18.**



#### <span id="page-25-2"></span>*Table 23: Start-up timings*



### *Figure 7: Start-up timings*

*9 Using nominal tick time, excluding tick time variations.*

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## <span id="page-26-0"></span>**Unique features 19.**

Thanks to its state of the art mixed signal chain, the MLX90329 offers the possibility to calibrate several types of resistive Wheatstone bridge technologies allowing the MLX90329 users to reach an outstanding overall sensor accuracy. The MLX90329 is robust for harsh automotive environments like large temperature range, overvoltage conditions and external EMC disturbances.

The MLX90329 allows the compensation of sensor nonlinear variations over temperature as well as compensates for the sensor pressure signal non linearity. Several parameters can be programmed through the application pins in the MLX90329 to set clamping levels or filter settings to choose for the best trade-off between signal chain noise and speed. The MLX90329 can also diagnose several error conditions like sensor connections errors.

The sensor bias Vbrg which is supplying the external pressure sensor is generated using a regulator. The target sensor supply is 6/7VDDA or typically 3V. The current through the bridge resistance is mirrored and divided so that it can be fed to an IV convertor. This IV converted signal is a measure for the external temperature so that it can be used for the calibration of the pressure sensor.

MLX90329 can interface an external NTC and provide the linearized temperature information together with the pressure signal on the SENT output. This NTC is factory calibrated by Melexis.



*Figure 8: MLX90329 Block Diagram* 





## <span id="page-27-0"></span>**Application Information 20.**

The MLX90329 only needs 2 capacitors in the application. A 100nF decoupling capacitor connected between the supply line and the ground a 2.2nF load between the SENT output pin and the ground.

Optionally an NTC can be connected to pin 7. It is recommended to place a 10nF capacitor in parallel with the NTC to improve EMC performance. In case no NTC is used, pin 7 has to be connected to GND.

MLX90329 has built in EMC protection for the sensor supply and sensing element input pins. Therefore it is advised not to place any external capacitors between the sensing element and the interface. Capacitors on the sensor supply or the inputs can even disturb the normal operation of the interface.

These recommendations for external components are however only providing a basic protection. Depending on the module design and the EMC requirements different configurations can be needed.



*Figure 9: MLX90329 basic application schematic* 





# <span id="page-28-0"></span>**21. Standard information regarding manufacturability of Melexis products with different soldering processes**

Our products are classified and qualified regarding soldering technology, solderability and moisture sensitivity level according to following test methods:

### **Reflow Soldering SMD's (Surface Mount Devices)**

- **IPC/JEDEC J-STD-020** Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices (classification reflow profiles according to table 5-2)
- **EIA/JEDEC JESD22-A113** Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing (reflow profiles according to table 2)

#### **Wave Soldering SMD's (Surface Mount Devices) and THD's (Through Hole Devices)**

- **EN60749-20**
- Resistance of plastic- encapsulated SMD's to combined effect of moisture and soldering heat
- EIA/JEDEC JESD22-B106 and EN60749-15 Resistance to soldering temperature for through-hole mounted devices

#### **Iron Soldering THD's (Through Hole Devices)**

 EN60749-15 Resistance to soldering temperature for through-hole mounted devices

#### **Solderability SMD's (Surface Mount Devices) and THD's (Through Hole Devices)**

**EIA/JEDEC JESD22-B102 and EN60749-21** Solderability

For all soldering technologies deviating from above mentioned standard conditions (regarding peak temperature, temperature gradient, temperature profile etc) additional classification and qualification tests have to be agreed upon with Melexis.

The application of Wave Soldering for SMD's is allowed only after consulting Melexis regarding assurance of adhesive strength between device and board.

Melexis is contributing to global environmental conservation by promoting **lead free** solutions. For more information on qualifications of **RoHS** compliant products (RoHS = European directive on the Restriction Of the use of certain Hazardous Substances) please visit the quality page on our website: <http://www.melexis.com/quality.aspx>

### <span id="page-28-1"></span>**ESD Precautions 22.**

Electronic semiconductor products are sensitive to Electro Static Discharge (ESD). Always observe Electro Static Discharge control procedures whenever handling semiconductor products.





# <span id="page-29-0"></span>**Package Information 23.**



*Figure 10: Package drawing* 

#### Package dimensions in mm



### Package dimensions in inch



*Table 24: Package dimensions in mm and inch* 



# <span id="page-30-0"></span>**Contact 24.**

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